Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/938,174	LEUNG ET AL.	
Examiner	Art Unit	
Haresh Patel	2154	

	SEAR	CHED	
Class	Subclass	Date	Examiner
709	231	5/22/06	H.P.
718	100	1	
713	300,310		
713	330,340		
719	310		
715	866		
340	870.18		
714	810		
455	103		
709	200-203		
709	217-236	→	

INT	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			
709	231,217	5/22/06	H.P.			
713	300,330					
713	340	1	₩			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST, US-PAT, US-PUB, EPO, JPO. IEEE Xplore, Deowend ACM Digital libromy Coogle	St2106	H.P.	